PVA TePla

OKOS

SCANNING ACOUSTIC MICROSCOPE

VUE 250-P-NexGen

Semiconductor Package Failure Analysis
voids · disbonds · cracks · delamination · internal defects

Customer Interface
Dual 22" HD LED Monitors

Fixtures
Open Tank Bed

Instrumentation
Digital Pulser Receiver
Digitizer (Max 4 GHz)

User Experience Elements
HD LED Lighting
Stainless Steel Tank

Maintenance Free Scan Axis

Motor:	Linear Servo
Max Velocity:	500 mm/s
Accuracy & Repeatability:	+/- 5.0 micron
Scan Envelope:	322.6 mm

Low Maintenance Step Axis:

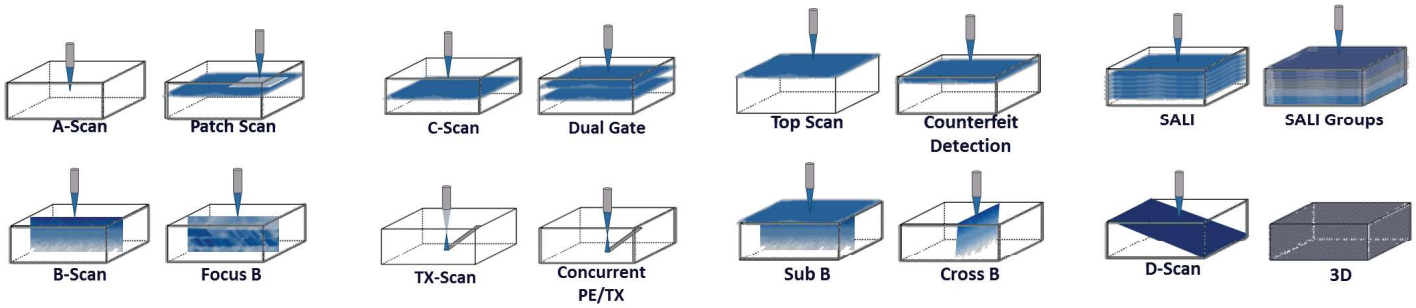
Step Envelope	136 mm

Low Maintenance Focus Axis:

Focus Envelope	35 mm

Dimensions:
700 mm x 560 mm x 470 mm (W/D/H)
81 kg

Full Jedec Tray Inspection



GET IN TOUCH

OKOS Solutions LLC, 7036 Tech Circle, Manassas, VA 20109, USA
www.okos.com I info@okos.com I +1 703.880.3039 I

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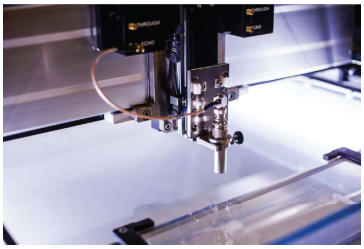
OKOS Digital Imaging System (ODIS)

Included Software Modes:

- Basic (user friendly)
- Advanced (detailed analysis)
- Production (automated scanning)
- Off-line Analysis (virtual scanning)



OKOS Digital Imaging System (ODIS)

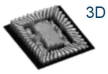
VUE 250-P imaging power surpasses modern standards delivering premium FA Lab features to semiconductor fabrication facilities. ODIS is the latest Acoustic Microscopy software with rich technical content built on current platforms and industry feedback. Advanced analysis is provided through quantitative tools for measurement and classification of parts.

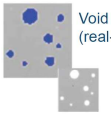
The Analysis version of ODIS allows non-scanning computers to virtually scan, view, and analyze data for simultaneous real-time analysis or post collection review.

- Counterfeit Detection
- Product Inspection
- Product Reliability
- Quality Control
- Process Validation
- Failure Analysis
- Vendor Qualification
- R&D

Application Specific Transducers

for the highest quality resolution.
Multiple transducer design for enhanced scan capability.


3D Imaging

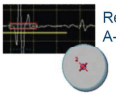

Void Gating (real-time)


C-scan with Multi-gate SALI & SALI Groups


Cluster Analysis (post processing)


Advanced Time-of-Flight & Thickness Measurements


Threshold Mapping (post processing)


Real-time A-scan & A-scan Capture


B-scan & SLICE

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www.okos.com I info@okos.com I +1 703.880.3039 I